

S(3)—O(34)—C(34)—C(33)	96.2 (2)
S(3)—O(34)—C(34)—C(35)	-145.7 (2)
S(4)—C(36)—C(35)—O(35)	82.0 (2)
S(4)—C(36)—C(35)—C(34)	-159.6 (2)

The data collection was extended to include the measurement of the intensities of the Friedel opposites of all reflections in the unique octant with $2\theta < 50^\circ$. Friedel pairs were not averaged during the data reduction so that the effects of anomalous dispersion could be used for the determination of the absolute configuration.

The displacement ellipsoids for one of the benzoyl groups indicate the presence of slight disorder or thermal motion, however, a disordered model could not be refined satisfactorily.

The absolute configuration was determined by using the *CRYSTALS* program system (Watkin, Carruthers & Betteridge, 1985) to refine the final atomic coordinates together with the enantiopole parameter (Flack, 1983). The refined value of the enantiopole parameter was 0.04 (5), thus confirming that the atomic coordinates represented the correct enantiomorph.

Data collection: *MSC/AFC Diffractometer Control Software* (Molecular Structure Corporation, 1991). Cell refinement: *MSC/AFC Diffractometer Control Software*. Data reduction: *TEXSAN PROCESS* (Molecular Structure Corporation, 1989). Program(s) used to solve structure: *SHELXS86* (Sheldrick, 1990). Program(s) used to refine structure: *TEXSAN LS*. Molecular graphics: *ORTEPII* (Johnson, 1976). Software used to prepare material for publication: *TEXSAN FINISH*.

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Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: PA1147). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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A Dimeric Uracil Derivative

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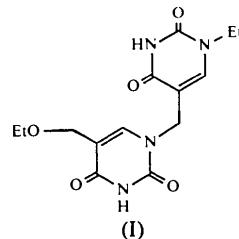
(Received 25 October 1993; accepted 26 January 1994)

Abstract

The structure of a dimeric uracil derivative, 5-ethoxy-methyl-1'-ethyl-1,5'-methylenedi-2,4(1*H*,3*H*)-pyrimidinedione, $C_{14}H_{18}N_4O_5$, was determined. The two uracil groups present in this molecule are almost identical. The torsion angles involving the bonds connecting the two uracil moieties, C6—N1—C13—C14 and C19—C14—C13—N1, are 77.5 (3) and 75.9 (3) $^\circ$, respectively.

Comment

Since the discovery of the new anti-HIV-1 (human immunodeficiency virus type 1) lead compound HEPT, 1-[[(2-hydroxyethoxy)methyl]-6-(phenylthio)thymine (Miyasaka *et al.*, 1989), extensive synthetic studies of HEPT analogues have been carried out (for a recent report see Tanaka *et al.*, 1992). The title compound, (I), was obtained as a by-product during the preparation of 5-ethoxymethyl-1-ethyluracil, which was then converted to the required regiosomeric analogue of HEPT by a procedure based on lithiation chemistry (Tanaka *et al.*, 1994).



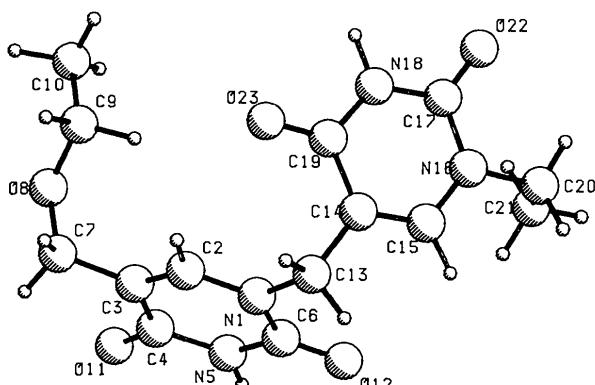


Fig. 1. The molecular structure of the title compound with the atom-numbering scheme.

Experimental

Crystal data

$C_{14}H_{18}N_4O_5$

$M_r = 322.32$

Triclinic

$P\bar{1}$

$a = 9.326$ (2) Å

$b = 11.991$ (3) Å

$c = 7.964$ (1) Å

$\alpha = 94.58$ (2)°

$\beta = 105.39$ (2)°

$\gamma = 113.84$ (3)°

$V = 767.5$ (3) Å³

$Z = 2$

$D_x = 1.395$ Mg m⁻³

Data collection

Rigaku AFC-5 diffractometer

$w/2\theta$ scans

Absorption correction: none

2531 measured reflections

2288 independent reflections

2099 observed reflections

[$F > 3\sigma(F)$]

Refinement

Refinement on F

$R = 0.042$

$wR = 0.043$

$S = 1.81$

2099 reflections

280 parameters

All H-atom parameters refined

Cu $K\alpha$ radiation

$\lambda = 1.5418$ Å

Cell parameters from 20 reflections

$\theta = 28.0-30.0^\circ$

$\mu = 0.865$ mm⁻¹

$T = 297$ K

Prism

$0.30 \times 0.30 \times 0.50$ mm

Clear

$R_{\text{int}} = 0.013$

$\theta_{\text{max}} = 60^\circ$

$h = -10 \rightarrow 10$

$k = -13 \rightarrow 13$

$l = 0 \rightarrow 8$

3 standard reflections

monitored every 150

reflections

intensity decay: <3%

$$w = 1/[\sigma^2(F) + 0.005F^2]$$

$$(\Delta/\sigma)_{\text{max}} = 0.18$$

$$\Delta\rho_{\text{max}} = 0.14 \text{ e } \text{\AA}^{-3}$$

$$\Delta\rho_{\text{min}} = -0.24 \text{ e } \text{\AA}^{-3}$$

Atomic scattering factors from International Tables for X-ray Crystallography (1974, Vol. IV)

C4	0.5830 (2)	0.8300 (1)	0.4882 (2)	0.046 (1)
N5	0.4244 (2)	0.8048 (1)	0.3857 (2)	0.046 (1)
C6	0.3092 (2)	0.8286 (1)	0.4390 (2)	0.043 (1)
C7	0.8014 (3)	0.9241 (2)	0.7940 (3)	0.061 (1)
O8	0.8101 (2)	0.8206 (1)	0.8643 (2)	0.076 (1)
C9	0.7393 (3)	0.7975 (2)	1.0033 (3)	0.074 (1)
C10	0.7432 (5)	0.6827 (3)	1.0597 (5)	0.105 (2)
O11	0.6707 (2)	0.8016 (1)	0.4208 (2)	0.070 (1)
O12	0.1703 (1)	0.8002 (1)	0.3406 (2)	0.059 (1)
C13	0.2472 (2)	0.9132 (2)	0.6864 (3)	0.047 (1)
C14	0.1324 (2)	0.7970 (1)	0.7275 (2)	0.042 (1)
C15	-0.0218 (2)	0.7267 (2)	0.6169 (3)	0.047 (1)
N16	-0.1263 (2)	0.6159 (1)	0.6448 (2)	0.044 (1)
C17	-0.0775 (2)	0.5714 (1)	0.7910 (2)	0.046 (1)
N18	0.0793 (2)	0.6453 (1)	0.9064 (2)	0.046 (1)
C19	0.1923 (2)	0.7564 (1)	0.8846 (2)	0.044 (1)
C20	-0.2896 (2)	0.5379 (2)	0.5097 (3)	0.059 (1)
C21	-0.2779 (5)	0.4529 (3)	0.3710 (4)	0.086 (1)
O22	-0.1677 (1)	0.4716 (1)	0.8175 (2)	0.058 (1)
O23	0.3328 (1)	0.8110 (1)	0.9953 (1)	0.053 (1)

Table 2. Selected geometric parameters (Å, °)

N1—C2	1.372 (2)	C9—C10	1.492 (6)
N1—C6	1.383 (2)	C13—C14	1.500 (3)
N1—C13	1.478 (3)	C14—C15	1.336 (2)
C2—C3	1.336 (4)	C14—C19	1.436 (3)
C3—C4	1.443 (3)	C15—N16	1.370 (2)
C3—C7	1.496 (3)	N16—C17	1.365 (3)
C4—O11	1.226 (3)	N16—C20	1.473 (2)
C4—N5	1.380 (3)	C17—O22	1.227 (2)
N5—C6	1.373 (3)	C17—N18	1.370 (2)
C6—O12	1.212 (2)	N18—C19	1.383 (2)
C7—O8	1.424 (4)	C19—O23	1.235 (2)
O8—C9	1.423 (3)	C20—C21	1.499 (5)
C2—N1—C6	121.2 (2)	N1—C13—C14	110.9 (2)
C2—N1—C13	120.8 (1)	C15—C14—C19	119.0 (1)
C6—N1—C13	117.8 (1)	C15—C14—C13	121.6 (2)
C3—C2—N1	123.7 (1)	C19—C14—C13	119.3 (1)
C2—C3—C4	118.5 (2)	C14—C15—N16	123.1 (2)
C2—C3—C7	122.4 (2)	C17—N16—C15	121.1 (1)
C4—C3—C7	119.2 (2)	C17—N16—C20	118.6 (1)
O11—C4—N5	119.8 (2)	C15—N16—C20	120.2 (2)
O11—C4—C3	125.5 (2)	O22—C17—N16	122.3 (1)
N5—C4—C3	114.7 (2)	O22—C17—N18	122.1 (2)
C6—N5—C4	127.7 (1)	N16—C17—N18	115.6 (1)
O12—C6—N5	123.3 (2)	C17—N18—C19	126.3 (2)
O12—C6—N1	122.5 (2)	O23—C19—N18	119.6 (2)
N5—C6—N1	114.1 (1)	O23—C19—C14	125.5 (1)
O8—C7—C3	112.4 (1)	N18—C19—C14	114.9 (1)
C9—O8—C7	112.8 (2)	N16—C20—C21	111.3 (2)
O8—C9—C10	109.0 (3)		

Initial structure analysis was performed, with a continuous process connected to the data collection, using the fully automatic FASE procedure (Yamaguchi, 1993). The structure was solved by direct methods, which is included in FASE. Further refinement was by a full-matrix least-squares method.

Data collection: AFD (Rigaku Corporation, 1985a). Cell refinement: AFD. Data reduction: FASE. Program(s) used to solve structure: SAP/85 (Yao *et al.*, 1985). Program(s) used to refine structure: RCRYSTAN (Rigaku Corporation, 1985b). Molecular graphics: ACV (Stardent Computer Inc., 1990). Software used to prepare material for publication: XPACK (Yamaguchi, 1987).

Table 1. Fractional atomic coordinates and equivalent isotropic displacement parameters (Å²)

$$U_{\text{eq}} = (1/3)\sum_i \sum_j U_{ij} a_i^* a_j^* \mathbf{a}_i \cdot \mathbf{a}_j$$

	x	y	z	U_{eq}
N1	0.3659 (2)	0.8898 (1)	0.6150 (2)	0.039 (1)
C2	0.5234 (2)	0.9201 (1)	0.7236 (2)	0.041 (1)
C3	0.6320 (2)	0.8925 (1)	0.6708 (2)	0.043 (1)

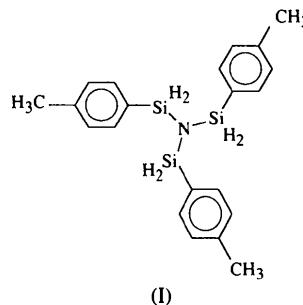
Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCR (Reference: AS1096). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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the deviation from a planar N-atom coordination geometry could be related to the electronegative bonding partners N in hydrazines and O in hydroxylamines, and lone-pair repulsion effects, as supported by theoretical calculations (Mitzel, Hofmann, Waterstradt, Schleyer & Schmidbaur, 1994).

All trisilylamines studied until now show a completely flat geometry at the N atoms. $(H_3Si)_3N$ (Hedberg, 1955; Beagley & Conrad, 1970), $(Me_2HSi)_3N$ (Ebsworth, Murray, Rankin & Robertson, 1981) and $(Me_3Si)_3N$ (Anderson, Rankin & Robertson, 1990) were studied by electron diffraction in the gas phase, and the solid-state structures of a few compounds were elucidated by single-crystal X-ray diffraction: $(H_3Si)_3N$ (Barrow & Ebsworth, 1984), $(Cl_3Si)_3N$ and $(Cl_3Si)N(SiCl_2)_2N(SiCl_3)$ (Wannagat, Flindt, Brauer, Büger & Dörrenbach, 1989), $(PhH_2Si)_3N$ (Mitzel, Schier & Schmidbaur, 1992) and some amines with mixed ligands (Mitzel, Schier, Beruda & Schmidbaur, 1992).



The present investigation of tris(*p*-tolylsilyl)amine, (I), is part of a more extensive study of the factors contributing to nitrogen planarization in Si-N systems.

A perspective view showing the atomic numbering scheme is given in Fig. 1. Selected bond lengths and angles are listed in Table 2.

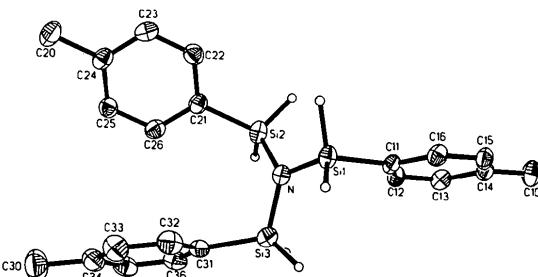


Fig. 1. Plot of tris(*p*-tolylsilyl)amine. Displacement ellipsoids are plotted at the 50% probability level.

Abstract

The title compound, $C_{21}H_{27}NSi_3$, shows a virtually planar coordination geometry of the N atom. Unlike in $(PhH_2Si)_3N$, the three *p*-tolylsilyl substituents are not related by crystallographic symmetry.

Comment

The planar configuration of the N atom is the most striking structural feature of most of the silylated nitrogen compounds (Lucevics, Pudova & Strukokovich, 1989). Only a few exceptions of this general rule are known: aminosilanes with NH_2 substituents at bulky organosilyl groups (Ruhlandt-Senge, Bartlett, Olmstead & Power, 1993), two silylhydrazine compounds (Dressler, Niecke, Pohl, Saak, Schoeller & Schaefer, 1986; Schrenk & Matthes, 1988), and silylated hydroxylamines (Mitzel, Angermaier & Schmidbaur, 1994). In the latter two cases,

Experimental

Tris(*p*-tolylsilyl)amine (I) was prepared by a known method (Mitzel, Riede, Schier, Paul & Schmidbaur, 1993) and crystallized by slowly cooling the melt diluted with a minimum amount of hexane to 253 K.